

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 1 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	99/62930	12-1999	WO	Dancik	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Burlingame, A. L. et al, Analytical Chemistry 1968, 40, 13-19.
	V	Venkataraghavan, R. et al, Organic Mass Spectrometry 1969, 2, 1-15.
	W	Smith, D. H. Analytical Chemistry 1972, 44, 536-547.
	X	Kwok, K.-S. et al, Journal of the American Chemical Society 1973, 95, 4185-4194.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 2 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dromey, R. G. Analytical Chemistry 1976, 48, 1464-1469.
	V	Hollos, J. Magyar Kemiai Folyoirat 1976, 82, 512-513.
	W	Damen, H. et al, Analytica Chimica Acta 1978, 103, 289-302.
	X	Rasmussen, G. T. et al, Journal of Chemical Information and Computer Sciences 1979, 19, 98-104.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 3 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mun, In Ki et al, Analytical Chemistry 1981, 53, 179-182.
	V	Brotherton, H. O. et al, Analytical Chemistry 1983, 55, 549-553.
	W	Hines, W. M. et al, Journal of the American Society for Mass Spectrometry 1992, 3, 326-336.
	X	Yates, J. R., III et al, Analytical Biochemistry 1993, 214, 397-408.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 4 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Eng, J. K. et al, Journal of the American Society for Mass Spectrometry 1994, 5), 976-989.
	V	Mann, M. et al, Analytical Chemistry 1994, 66, 4390-4399.
	W	Fang, H. et al, Shengwu Huaxue Yu Shengwu Wuli Jinzhan 1995, 22, 361-366.
	X	Yates, J. R., III et al, Analytical Chemistry 1995, 67, 1426-1436.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 5 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Stein, S. E. Journal of the American Society for Mass Spectrometry 1995, 6, 644-655.
	V	McLuckey, S. A. et al, Journal of Mass Spectrometry 1995, 30, 1222-1229.
	W	Yates, J. R., III et al, Analytical Chemistry 1995, 67, 3202-3210.
	X	Bonner, R. et al, Rapid Communications in Mass Spectrometry 1995, 9, 1077-1080.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 6 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Qian, M. G. et al, Rapid Communications in Mass Spectrometry 1996, 10, 1209-1214.
	V	Windig, W. et al, Analytical Chemistry 1996, 68, 3602-3606.
	W	Fernandez-de-Cossio, J. et al, Rapid Communications in Mass Spectrometry 1998, 12, 1867-1878.
	X	Fleming, C. M. et al, Journal of Chromatography, A 1999, 849, 71-85.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/877,182	Applicant(s)/Patent Under Reexamination LIEBLER ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 7 of 7

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tong, H. et al, Journal of the American Society for Mass Spectrometry 1999, 10, 1174-1187.
	V	Gras, R. et al, Electrophoresis 1999, 20, 3535-3550.
	W	Moore, R. E. et al, Journal of the American Society for Mass Spectrometry 2000, 11, 422-426.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.